

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Shunpei YAMAZAKI et al.

Filing Date: June 29, 2001

Group Art Unit: 2823

1017 U.S. PTO
09/894125
06/29/01

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
BK	5,594,569	01/14/1997	Konuma et al.			
BK	5,643,826	07/01/1997	Ohtani et al.			
BK	5,923,962	07/13/1999	Ohtani et al.			
BK	5,854,096	12/29/1998	Ohtani et al.			
BK	5,616,506	04/01/1997	Takemura			
BK	5,696,386	12/09/1997	Yamazaki			
BK	5,712,191	01/27/1998	Nakajima et al.			
BK	5,888,857	03/30/1999	Zhang et al.			
BK	5,960,323	09/28/1999	Wakita et al.			
BK	6,093,937	07/25/2000	Yamazaki et al.			
BK	6,121,076	09/19/2000	Zhang et al.			
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BK	5,923,966	07/13/1999	Teramoto et al.			
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BK	5,869,363	02/1999	Yamazaki et al.			
BK	5,616,932	04/01/1997	Sano et al.			
BK	5,910,015	06/08/1999	Sameshima et al.			

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Document Number	Date	Country	Class	Subclass	Translation Yes	Translation No
07-130652	05/19/1995	Japan			Abstract	
08-078329	03-22-1996	Japan			Abstract	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	"Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Ryuichi Shimokawa et al., Japanese Journal of Applied Physics, Vol. 27, No. 5, pages 751-758, 1988.
	"Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLCDC Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability", H. Furue et al., SID 1998
	"A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time", T. Yoshida et al., SID DIGEST, pages 841-844, 1997.

Examiner

Brook Kebede

Date Considered

April 20, 2002

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete if Known

Application Number

June 29, 2001

Filing Date

First Named Inventor

Shunpei YAMAZAKI et al.

Group Art Unit

2823

Examiner Name

B. Kebede

Attorney Docket Number

740756-2330

Sheet

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of

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U.S. PATENT DOCUMENTS

Examiner Initials [*]	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
		5,147,826		Liu et al.	09/15/1992	
		5,461,250		Burghartz et al.	10/24/1995	
		4,986,213		Yamazaki et al.	01/22/1991	
		6,124,154		Miyasaka	09/26/2000	
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Examiner Initials [*]	Cite No. ¹	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴ Kind Code ⁵ (if known)				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials [*]	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Dorin et al., "Chemistry The Study of Matter", 1992, pp. 532, Prentice Hall	
		Aya et al., "Improvement of SPC poly-Si Film Using the ELA Method", September 11-12, 1997, pp. 167-170, AM-LCD.	
		Abe et al., High-Performance Poly-Crystalline Silicon TFT's Fabricated Using the SPC and ELA Methods", July 9-10, 1998, pp. 85-88, AM-LCD.	
		"Thresholds antiferroelectricity in liquid crystals and its application to displays", S. Inui et al., J. Mater. Chem., 6(4), pages 671-673, 1996.	
BK		U.S. Patent Application Serial No. 09/369,158 "Semiconductor Device and Method of Manufacturing the Same".	
BK		U.S. Patent Application Serial No. 09/352,194 "Crystalline Semiconductor Thin Film, Method of Fabricating the Same Semiconductor Device, and Method of Fabricating the Same".	
Examiner Signature	Brook Kebede		Date Considered April 20, 2002